Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/724,771	CHEN ET AL.	
Examiner	Art Unit	
Justin Krause	3682	

	SEAR	CHED	
Class	Subclass	Date	Examiner
384	100 107 113 114 115 118 119 120 286 322	12/5/2005	JMK
384	397		
360	99.08		
417	354 423.12		
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	DATE	EXMR
See EAST history	12/5/2005	JMK
PLUS search		
Search from T. Hannon		